

Issue Classification 	Application/Control No.	Applicant(s)/Patent under Reexamination
	10/017,325	SHIBATA ET AL.
	Examiner	Art Unit
	Junghwa M. Im	2811

ISSUE CLASSIFICATION									
ORIGINAL		CROSS REFERENCE(S)							
CLASS	SUBCLASS	CLASS	SUBCLASS (ONE SUBCLASS PER BLOCK)						
257	94	257	80	94	199	77	96	194	97
INTERNATIONAL CLASSIFICATION		438	22						
H	0	1	L	33/00					
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Junghwa Im 1-18-2006 (Assistant Examiner) (Date) <i>Junghwa Im</i>				EDDIE LEE SUPERVISORY PATENT EXAMINER TECHNOLOGY CENTER 2800 Primary Examiner <i>Lee</i> (Date) 1/21/06				Total Claims Allowed: 13	
Malandra Polenka 2/1/06 (Legal Instruments Examiner) (Date)								O.G. Print Claim(s): 1	O.G. Print Fig: 1

<input type="checkbox"/> Claims renumbered in the same order as presented by applicant		<input type="checkbox"/> CPA		<input type="checkbox"/> T.D.		<input type="checkbox"/> R.1.47	
Final	Original	Final	Original	Final	Original	Final	Original
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5	5	35	65	95	125	155	185
6	6	36	66	96	126	156	186
	7	37	67	97	127	157	187
7	8	38	68	98	128	158	188
	9	39	69	99	129	159	189
8	10	40	70	100	130	160	190
9	11	41	71	101	131	161	191
10	12	42	72	102	132	162	192
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13	15	45	75	105	135	165	195
	16	46	76	106	136	166	196
17		47	77	107	137	167	197
18		48	78	108	138	168	198
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22		52	82	112	142	172	202
23		53	83	113	143	173	203
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26		56	86	116	146	176	206
27		57	87	117	147	177	207
28		58	88	118	148	178	208
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